

P1671.5

Submitter Email: chris.gorringe@eads-ts.com
Type of Project: Revision to IEEE Standard 1671.5-2008
PAR Request Date: 15-Apr-2010
PAR Approval Date: 17-Jun-2010
PAR Expiration Date: 31-Dec-2014
Status: PAR for a Revision to an existing IEEE Standard
Project Record: No Project Record
Root Project: 1671.5-2008 Edit Root Project Record

1.1 Project Number: P1671.5
1.2 Type of Document: Standard
1.3 Life Cycle: Full Use

2.1 Title: Standard for Automatic Test Markup Language (ATML) Test Adaptor Description

Old Title: IEEE Trial-Use Standard for Automatic Test Markup Language (ATML) for Exchanging Automatic Test Information via XML:Exchanging Test Adapter Information

3.1 Working Group: Test Information Integration Working Group (SASB/SCC20/TII_WG)

Contact Information for Working Group Chair

Name: Chris Gorringe
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Contact Information for Working Group Vice-Chair

None

3.2 Sponsoring Society and Committee: IEEE-SASB Coordinating Committees/SCC20 - Test and Diagnosis for Electronic Systems (SASB/SCC20)

Contact Information for Sponsor Chair

Name: Mike Seavey
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Contact Information for Standards Representative

None

4.1 Type of Ballot: Individual

4.2 Expected Date of submission of draft to the IEEE-SA for Initial Sponsor Ballot: 05/2013

4.3 Projected Completion Date for Submittal to RevCom: 05/2014

5.1 Approximate number of people expected to be actively involved in the development of this project: 10

5.2 Scope: This standard defines an exchange format, utilizing eXtensible Markup Language (XML), for both the static description of a test adaptor by defining the interface between the unit under test (UUT) and the test station, and the specific description of test adaptor instance information.

Old Scope: The scope of this trial-use standard is the definition of an exchange format, utilizing XML, for exchanging the test adaptor information by defining the interface between the UUT and the test station, which includes the description of the test adaptor (e.g., physical and electrical characteristics, capabilities/performance, and identification/classification).

5.3 Is the completion of this standard dependent upon the completion of another standard: Yes

If yes please explain: This standard is dependent upon the parent standard IEEE 1671 - Standard for Automatic Test Markup Language (ATML) for Exchanging Automatic Test Equipment and Test Information via XML. At the time of submission the Draft standard is in its ballot resolution phase, having already achieved enough affirmative votes to be submitted to RevCom.

5.4 Purpose: No purpose statement is required since this standard is intended for ISO IEC standardization.

Old Purpose: The purpose of this standard is to provide a standardized format to promote and facilitate interoperability between components of non-manual test systems, by allowing the exchange of test adaptor information. The

test adapter schema becomes a class of information that can be used within the ATML family of standards.

Each instance document contains the definition of a single test adapter model. The test adapter schema provides a structure for describing test adapter capabilities and structure.

This standard will allow test adapter information to be transportable across a variety of automatic test equipment (ATE) within the automotive, semiconductor, aerospace, and military industries.

5.5 Need for the Project: Adoption of the resultant standard will allow manufacturers of test adapters to meet the overall goals of interoperability embodied in this ATML family of standards.

5.6 Stakeholders for the Standard: Anticipated users of the ATML family of standards include the following:

Product (e.g., UUT) developers.

Product (e.g., UUT) maintainers.

TPS developers.

TPS maintainers.

ATE system developers.

ATE system maintainers.

Instrumentation developers.

Developers of ATML-based tools and systems.

Developers of prime mission equipment that use the supported UUT as a component.

Intellectual Property

6.1.a. Is the Sponsor aware of any copyright permissions needed for this project?: No

6.1.b. Is the Sponsor aware of possible registration activity related to this project?: No

7.1 Are there other standards or projects with a similar scope?: Do Not Know

If Yes please explain:

and answer the following

Sponsor Organization:

Project/Standard Number:

Project/Standard Date:

Project/Standard Title:

7.2 International Activities

a. Adoption

Is there potential for this standard (in part or in whole) to be adopted by another national, regional or international organization?: Yes

Organization: ISO

Technical Committee Name: TC93

Technical Committee Number: WG7

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b. Joint Development

Is it the intent to develop this document jointly with another organization?: No

c. Harmonization

Are you aware of another organization that may be interested in portions of this document in their standardization development efforts?: Do Not Know

Organization:

Technical Committee Name:

Technical Committee Number:

Contact Name:

Phone:

Email:

8.1 Additional Explanatory Notes (Item Number and Explanation): 1.3: This PAR has been submitted to update the previous Trial-Use Standard to Full Use and to align with the latest definitions and requirements of its parent standard IEEE Std 1671 - Standard for Automatic Test Markup Language (ATML) for Exchanging Automatic Test Equipment and Test Information via XML.

2.1, 5.2 & 5.4: The title, scope and purpose have all been changed to simplify and provide a consistent approach across the family of standards and to align their content with the latest IEEE Guide for PAR Review guidelines.

5.5: The goal is to have all the Full Use ATML 'dot' standards go to ballot at the same, or within a short window of each other so that all balloters can consider all changes at the same time. This will allow common changes to be considered across the family of 'Dot' standards.

The number of changes are not expected to be large, The revision is to bring all the trial use standards inline with the IEEE Std 1671 base standard.

5.3: A PAR is being requested at this time so as to allow initial work to be done to update the trial-use standard to a full use standard in line with the parent standard.